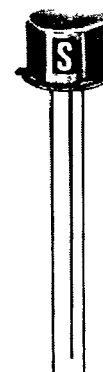


RADIATION RESISTANT NPN SILICON POWER TRANSISTORS**2N5527 2N5531****NPN SILICON POWER TRANSISTORS
RADIATION RESISTANT****5 AMPERES****FEATURES**

MEDIUM POWER
 RADIATION EXPOSURE LEVEL TO 5×10^{14} nvt
 TOTAL NEUTRON FLUX GREATER THAN 10 KEV

APPLICATIONS

POWER AMPLIFIER
 RADIATION ENVIRONMENTS
 ULTRA HIGH FREQUENCY

**TO-5****ABSOLUTE MAXIMUM RATINGS**

		<u>2N5527</u>	<u>2N5531</u>
V_{CBO}	COLLECTOR-BASE VOLTAGE	60 V	90 V
V_{CEO}	COLLECTOR-EMITTER VOLTAGE	40 V	75 V
V_{EBO}	EMITTER-BASE VOLTAGE	3 V	3 V
I_C	CONTINUOUS COLLECTOR CURRENT	5 A	5 A
I_B	CONTINUOUS BASE CURRENT	1 A	1 A
T_J	OPERATING JUNCTION TEMPERATURE	_____ -65°C to +200°C _____	
T_{stg}	STORAGE TEMPERATURE	_____ -65°C to +200°C _____	
$R_{\theta JC}$	THERMAL RESISTANCE, JUNCTION TO CASE	35°C/W	
P_D	POWER DISSIPATION (25°C)	5 W	

8-83-2R

RADIATION RESISTANT NPN SILICON POWER TRANSISTORS**2N5527 2N5531****ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)**

CHARACTERISTICS	SYMBOL	MIN.	MAX.	UNITS
COLLECTOR-EMITTER SUSTAINING VOLTAGE ⁽¹⁾ ($I_C = 50\text{ mA}$)	$V_{CE(sus)}$	40		V
2N5527		75		V
($I_C = 50\text{ mA}$, NOTE 2)		40		V
2N5531		75		V
COLLECTOR-CUTOFF CURRENT ($V_{CE} = 30\text{V}$, $V_{BE} = 0$, $T_C = 100^\circ\text{C}$)	I_{CEX}		1.0	mA
COLLECTOR-CUTOFF CURRENT ($V_{CB} = \text{RATED}$)	I_{CBO}		1.0	mA
($V_{CB} = \text{RATED}$, NOTE 2)			1.0	mA
COLLECTOR-CUTOFF CURRENT ($V_{CB} = 30\text{V}$)	$-I_{CBO}$		0.1	mA
($V_{CB} = 30\text{V}$, NOTE 2)			1.0	mA
COLLECTOR-CUTOFF CURRENT ($V_{CE} = \text{RATED}$)	I_{CEO}		50	mA
EMITTER CUTOFF CURRENT ($V_{EB} = 3.0\text{V}$)	I_{EBO}		1.0	mA
($V_{EB} = 3.0\text{V}$, NOTE 2)			1.0	mA
EMITTER FLOATING POTENTIAL ($V_{CB} = \text{RATED}$, $I_E = 0$)	V_{EBF}		1.0	V
DC CURRENT GAIN ⁽¹⁾ ($V_{CE} 5.0\text{V}$, $I_C = 0.5\text{A}$)	h_{FE}	40	300	
2N5527		25	300	
($V_{CE} 5.0\text{V}$, $I_C = 0.5\text{A}$)		40	200	
2N5531		30	150	
($V_{CE} 5.0\text{V}$, $I_C = 3.0\text{A}$)		25		
2N5527		20		
($V_{CE} 5.0\text{V}$, $I_C = 3.0\text{A}$)		15		
2N5531		7.0		
COLLECTOR-EMITTER SATURATION VOLTAGE ⁽¹⁾ ($I_C = 3.0\text{A}$, $I_B = 0.3\text{A}$)	$V_{CE(sat)}$		1.25	V
2N5527			1.25	V
($I_C = 3.0\text{A}$, $I_B = 0.5\text{A}$)			5.0	V
2N5531			5.0	V
($I_C = 5.0\text{A}$, $I_B = 0.2\text{A}$)			2.0	V
2N5527			3.0	V
($I_C = 5.0\text{A}$, $I_B = 0.25\text{A}$)	$V_{BE(sat)}$		1.5	V
2N5531			1.5	V
BASE-EMITTER SATURATION VOLTAGE ⁽¹⁾ ($I_C = 3.0\text{A}$, $I_B = 0.3\text{A}$)	$V_{BE(sat)}$		1.5	V
2N5527			1.5	V
($I_C = 3.0\text{A}$, $I_B = 0.5\text{A}$)	V_{BE}		1.5	V
2N5531			1.5	V
BASE-EMITTER VOLTAGE ($V_{CE} = 5.0\text{V}$, $I_C = 3.0\text{A}$)	V_{BE}		1.5	V
MAGNITUDE OF SMALL SIGNAL GAIN ($V_{CE} = 28\text{V}$, $I_C = 0.5\text{A}$, $f = 25\text{ MHz}$)	$[h_{fe}]$	8.0		
SMALL SIGNAL GAIN ($V_{CB} = 5.0\text{V}$, $I_C = 0.5\text{A}$, $f = 1.0\text{ KHz}$)	h_{fe}	20		
2N5527		15		
2N5531				
OUTPUT CAPACITANCE ($V_{CB} = 30\text{V}$, $f = 1.0\text{ MHz}$)	C_{obo}		75	pF
PROMPT PRIMARY PHOTO CURRENT ($\dot{\gamma} = 1 \times 10^9\text{ R/sec}$, $\epsilon \geq 1.0\text{ MeV}$, $V_{CB} = 10\text{V}$)	I_{ppc}		500	mA(PK)

Note 1: Pulsed 300 μsec , 1.8 Duty CycleNote 2: After exposure, $1 \times 10^{14}\text{ nvt}$, FLUX $\geq 10\text{ KEV}$

RADIATION RESISTANT NPN SILICON POWER TRANSISTORS

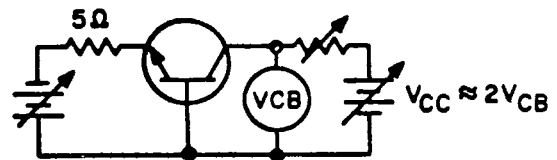
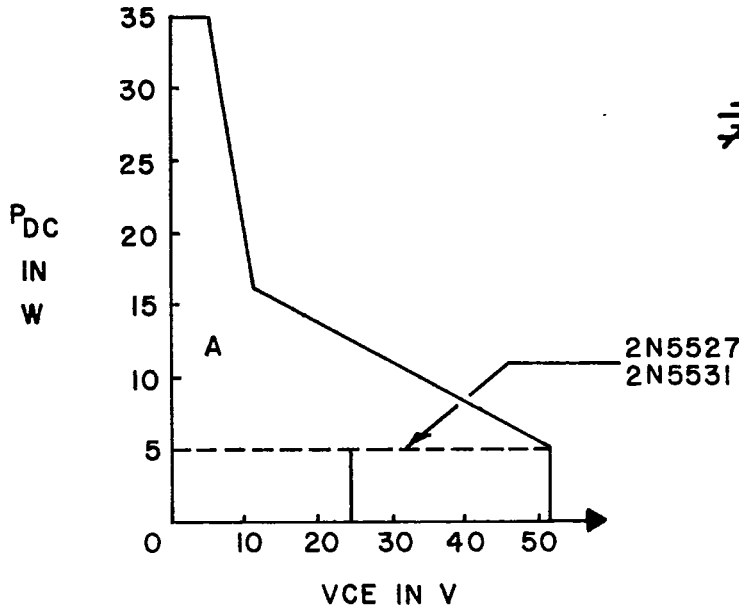
2N5527 2N5531

SAFE OPERATING AREA (SOAR) CONTINUOUS DC OPERATION

SOAR VALUES

TYPE NUMBER	V1 V	V2 V
2N5527	30	60
2N5531	65	90

- Conditions:
- $T_J = T_{CASE} + \Theta_{J-C} P_{DC} \leq 200^\circ C$
 - $P_{DC} = P_{DC \text{ max rating for specified transistor type}}$
 - $P_{DC} = P_{DC} = f(V_{CE}) \text{ Area A}$
 - $V_{CE} = 0.8V_1 \text{ rating for specified transistor type}$



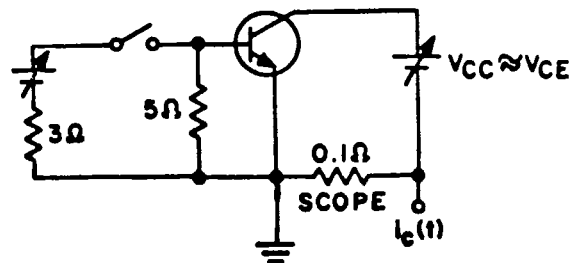
PULSED OPERATION

- Conditions:
- $T_J = T_{CASE} + \Theta_{J-C} P_{avg} \leq 200^\circ C$
 - $P_{avg} = \frac{1}{2ms} \int_0^{2ms} i_c v_{ce} dt \leq \text{the allowed DC}$

power dissipation for a V_{CE} equal to the highest v_{ce} applied to the transistor

- Operation in the active region should be limited to a maximum pulse width of $t_w = 1 \text{ ms}$ for Area B, $t_w = 0.5 \text{ ms}$ for Area C, $t_w = 0.25 \text{ ms}$ for Area D, and $t_w = 0.10 \text{ ms}$ for Area E. $t_r \leq 20 \mu s$ and $t_f \leq 20 \mu s$ for Areas B-E.

I_C (MAX)	B	C	D	E
$t_w \leq 1ms$	$t_w \leq 0.5ms$	$t_w \leq 0.25ms$	$t_w \leq 0.1ms$	
	$0.3V_1$	$0.4V_1$	$0.6V_1$	$0.8V_1$



RADIATION RESISTANT NPN SILICON POWER TRANSISTORS

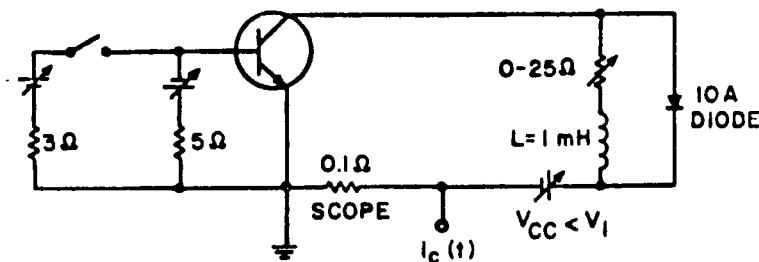
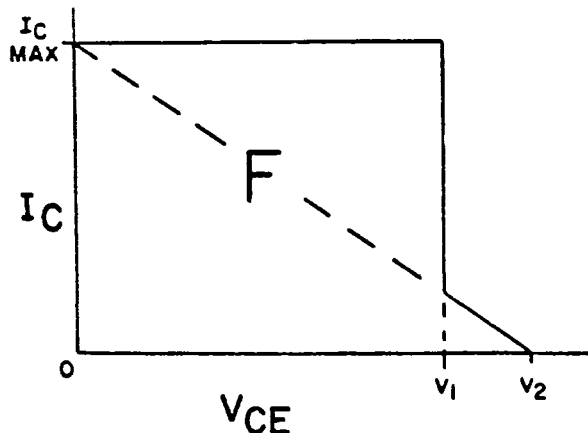
2N5527 2N5531

RESISTIVE AND CLAMPED INDUCTIVE SWITCHING

(Switching from saturation to cutoff)

Conditions:

1. $T_J = T_C + \Theta_{J-C} P_{avg} \leq 200^\circ C$
2. $P_{avg} = \frac{1}{2ms} \int_0^{2ms} i_c v_{ce} dt \leq PDC \text{ max.}$
3. For the resistive loadline, $L = 0$ and $V_{CC} = V_2$
4. $t_r \leq 2\mu s, t_f \leq 2\mu s$ in Area F

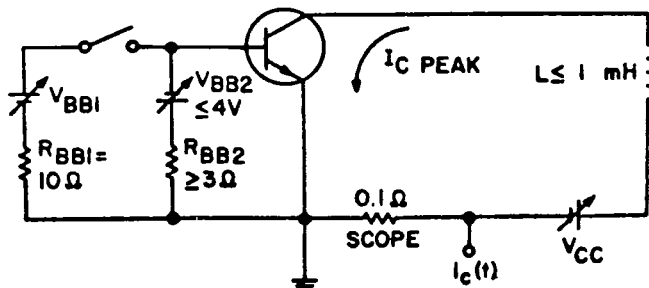
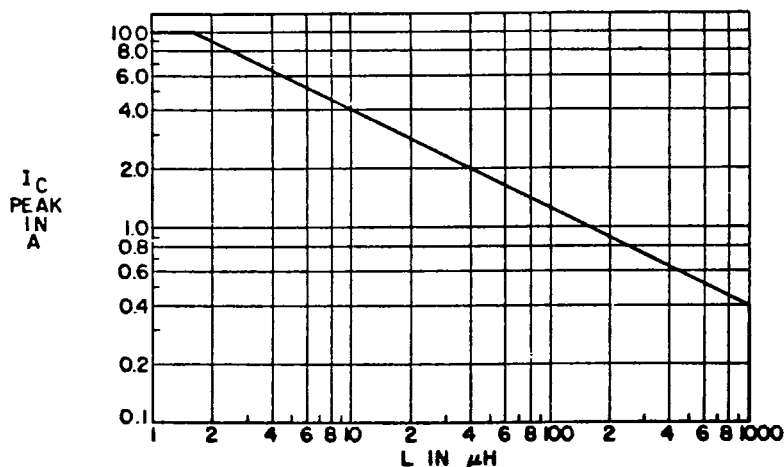


UNCLAMPED SWITCHING

(Switching from saturation to cutoff)

Conditions:

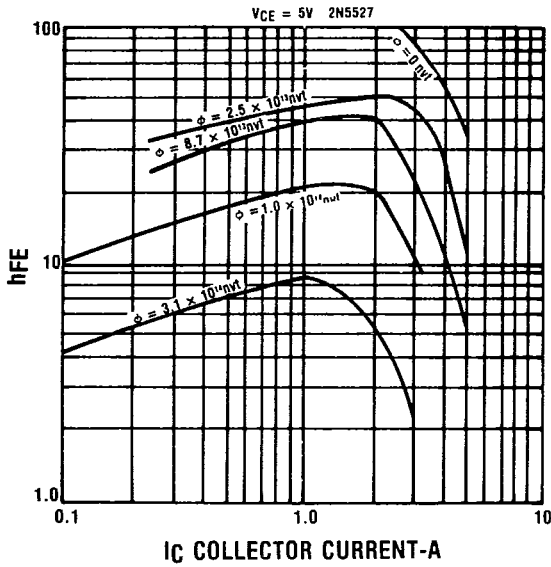
1. $T_J = T_C + \Theta_{J-C} P_{avg} \leq 200^\circ C$
2. $P_{avg} = \frac{1}{2ms} \int_0^{2ms} i_c v_{ce} dt \leq PDC \text{ max.}$
3. $I_C \text{ peak} \leq I_C \text{ max rating for specified transistor type}$
4. $\frac{1}{2} L I_C^2 \leq 80\mu Ws$



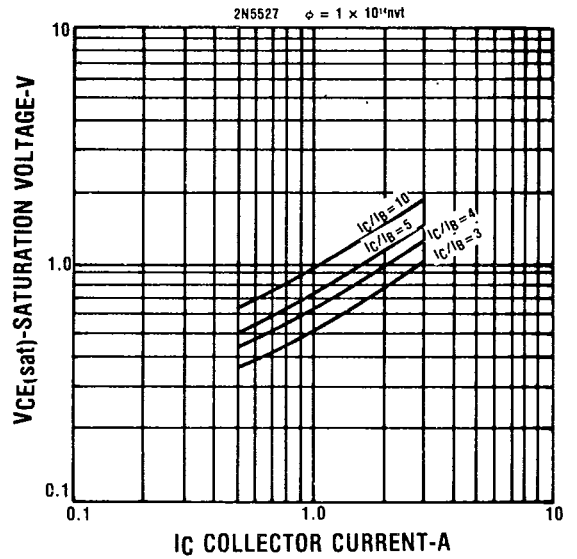
RADIATION RESISTANT NPN SILICON POWER TRANSISTORS

2N5527 2N5531

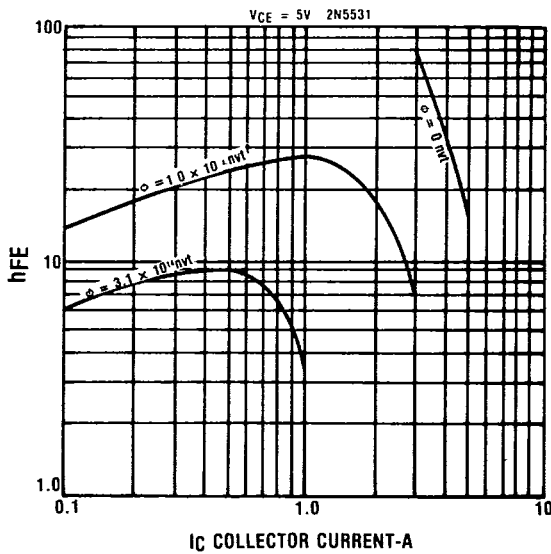
TYPICAL STATIC FORWARD CURRENT TRANSFER RATIO



TYPICAL COLLECTOR-EMITTER SATURATION VOLTAGE



TYPICAL STATIC FORWARD CURRENT TRANSFER RATIO



TYPICAL COLLECTOR-EMITTER SATURATION VOLTAGE

